SONY

ILX585K

10680 pixel x 6line CCD Linear Sensor (Color)

Description

The ILX585K is reduction type CCD linear sensor developed for color image scanner. This sensor reads A4-size documents at a density of 1200DPI and 2400DPI

Sensor Line Features 2400DPI staggered

Number of effective pixels:

64080 pixels(10680pixels \times 6)

Pixel size: $4\mu m \times 4\mu m (4\mu m pitch)$

Distance between main line: 48 \(\mu \) m(12 lines)

Distance between main line and Sub line: 8 µm(2 lines)



Single-sided readout

Ultra low lag

Single 12V power supply

Maximum data rate: 10MHz/Color Input clock pulse: CMOS 5V drive

Number of output: 3(R,G,B)

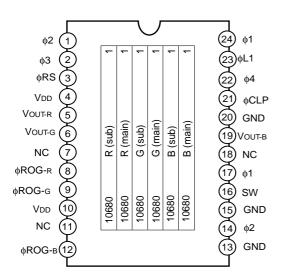
Package: 24pin Plastic-DIP(400mil)

Absolute Maximum Ratings

Supply voltage VDD 15

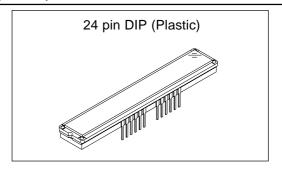
Operating temperature - 10to + 55

Pin Configuration(Top View)



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Pin Description

Pin No.	Symbol	Description	Pin No.	Symbol	Description
1	φ2	Clock pulse input	13	GND	GND
2	ф3	Clock pulse input	14	φ2	Clock pulse input
3	φRS	Clock pulse input	15	GND	GND
4	V _{DD}	12V power supply	16	SW	Switch(1200/2400dpi)
5	Vout-r	Signal output (red)	17	φ1	Clock pulse input
6	Vout-g	Signal output (green)	18	NC	NC
7	NC	NC	19	Vout-в	Signal output (blue)
8	φROG-R	Clock pulse input	20	GND	GND
9	φROG-G	Clock pulse input	21	φCLP	Clock pulse input
10	V _{DD}	12V power supply	22	φ4	Clock pulse input
11	NC	NC	23	φL1	Clock pulse input
12	фROG-в	Clock pulse input	24	φ1	Clock pulse input

Recommended Supply Voltage

Item	Min.	Тур.	Max.	Unit
VDD	11.4	12	12.6	٧

ClockCharacteristics

Item	Symbol	Min.	Тур.	Max.	Unit
Input capacity of \$1, \$2	Сф1, Сф2		3000		pF
Input capacity of ϕ RS	Сфяѕ		10		pF
Input capacity of ϕROG	Сфкоб		10		pF
Input capacity of \$4, \$41	Сфь1, Сф3, Сф4		20		pF

Clock Frequency

2400 DPI Staggered

Item	Symbol	Min.	Тур.	Max.	Unit
φ1, φ2, φL1	$f \varphi_1$, $f \varphi_2$, $f \varphi_{L1}$		1	5 ^{*1}	MHz
φ3, φ4, φRS	fφ3, fφ4, fφRS		1	10	MHz

^{*1} The frequency is 10MHz during the dump mode.

Input Clock Pulse Voltage Condition

Item			Тур.	Max.	Unit
φ1, φ2, φRS, φROG,	High level	4.75	5.0	5.25	V
φL1, φ3, φ4 pulse voltage	Low level	0	0	0.1	V

SW mode

	SW
HI (5V)	1200 DPI
LO (0V)	2400 DPI

Electrooptical Characteristics (Note 1, 2)

(Ta=25c,VDD=12V, ffRS=1MHz, Input clock=5Vp-p, Light source=3200K, IR cut filter CM500S (t = 1.0mm)

Item		Symbol	Min.	Тур.	Max.	Unit	Remarks
	Red	RR	1.4	2.0	2.6		
Sensitivity	Green	Rg	1.8	2.6	3.4	V/(Ix•s)	Note 2
	Blue	RB	1.4	2.0	2.6		
Sensitivity nonuniformity		PRNU		4	20	%	Note 3
Saturation output voltage	Saturation output voltage		2.0	2.5		V	Note 4
	Red	SER		1.25			
Saturation exposure	Green	SEG		0.96		lx•s	
oxposure .	Blue	SEB		1.25			Note 5
Saturation electrons		Nelec		30		Ke-	at 2.0V
Dark voltage average		Vdrk		0.1	1.6	mV	Note 6
Dark signal nonuniformity		DSNU		0.5	3.2	mV	
Supply current		I VDD		30	60	mA	Note 7
Total transfer efficiency		TTE	92	98		%	
Output impedance		ZO		360			

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Offset level	Vos		5.8		V	Note 8
Random Noise	NDσ		0.6		mV	Note 9

Notes:

- 1. In accordance with the given electrooptical characteristics, the black level is defined as the average value of D40, D41 to D73.
- 2. For the sensitivity test light is applied with a uniform intensity of illumination.
- 3. PRNU us defubed as indicated below. Ray iincidence conditions are the same as for Note 2. Vout=500mV(typ.)

$$PRNU = \frac{(V_{MAX} - V_{MIN})/2}{V_{AVE}} \times 100 [\%]$$

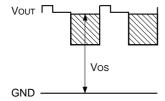
- 4. Use below the minimum value of the saturation output voltage.
- 5. Saturation exposure is defined as follows.

$$SE = \frac{V_{SAT}}{R}$$

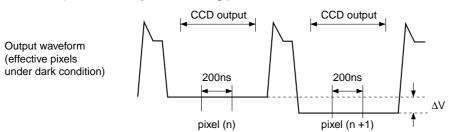
Where R indicates RR, Rg, RB and SE indicates SER, SEG, SEB.

- 6. Optical signal accumulated time τint stands at 4ms.
- 7. Supply current means the total current of this device.
- 8. Vos is defined as indicated bellow.

Vout indicates Vout-R, Vout-G, and Vout-B.



9. Random noise is defined on the output waveform with the external clamp and is defined as the standard deviation (sigma) of the output level difference between two adjacent effective pixels under no illumination (i.e.dark conditions) calculated by the following procedure.



- a) Two adjacent pixels (pixel n and n + 1) in one reading are fixed as measurement points.
- b) Each of the output level at video output periods is averaged over 200ns period to get V (n) and V (n + 1).
- c) V(n + 1) is subtracted from V(n) to get $f \notin V$.

$$f \notin V = Vn \bullet | V (n + 1)$$

d) The standard deviation of $f \notin V$ is calculated after procedure b) and c) are repeated 30 times (30 readings).

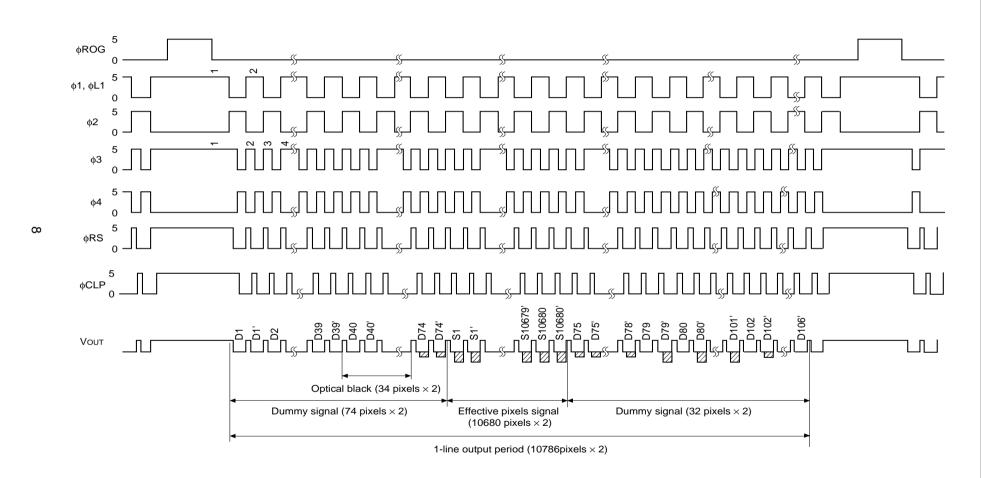
$$\Delta \overline{V} = \frac{1}{30} \sum_{i=1}^{30} |\Delta Vi| \qquad \sigma = \sqrt{\frac{1}{30} \sum_{i=1}^{30} (|\Delta Vi|^{\bullet} |\Delta V)^{2}}$$

- e) Procedure b), c) and d) are repeated 10 times to get sigma value.
- f) 10 sigma values are averaged.

$$\overline{\sigma} = \frac{1}{10} \sum_{i=1}^{10} \sigma_i$$

g) σ value calculated using the above procedure is observed $\sqrt{2}$ times larger than that measured relative to the ground level. So we specify random noise as follows.

ND
$$\sigma = \frac{1}{\sqrt{2}} \overline{\sigma}$$

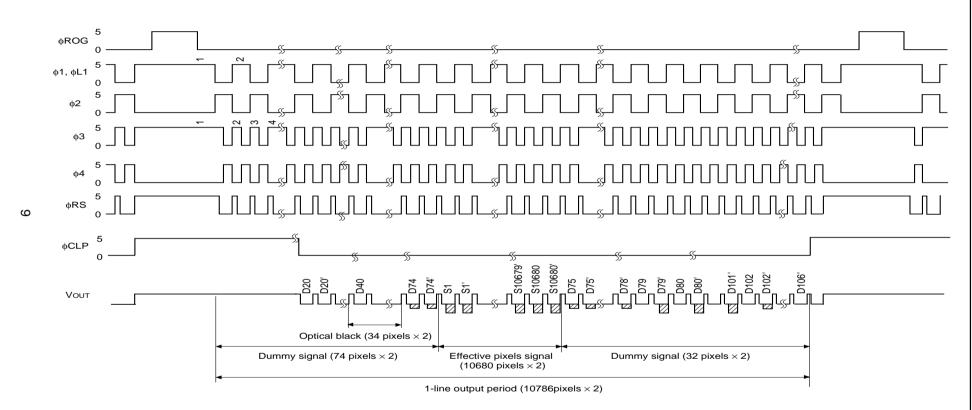


Note) The transfer pulses $(\phi 1, \phi 2)$ must have more than 10786 cycles.

The transfer pulses ($\phi 3,\, \phi 4)$ must have more than 21572 cycles.

Vour indicates Vour-R, Vour-G, Vour-B.

SW	m	ode	
SW		L	

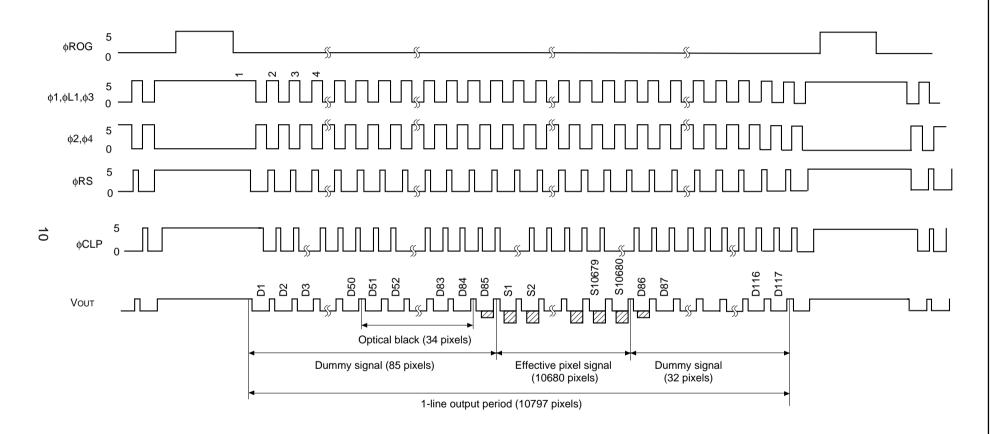


Note)The transfer pulses $(\phi 1, \phi 2)$ must have more than 10786 cycles.

The transfer pulses $(\phi 3,\, \phi 4)$ must have more than 21572 cycles.

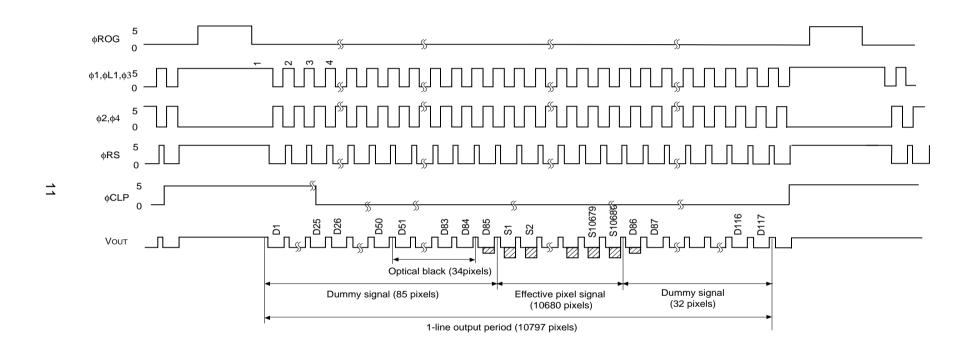
Vout indicates Vout-R, Vout-G, Vout-B.





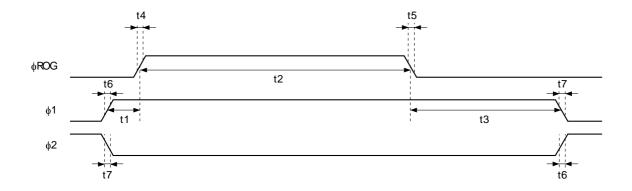
Note) The transfer pulses (ϕ 1, ϕ 2) must have more than 10797 cycles. Vout indicates Vout-R, Vout-G, Vout-B.



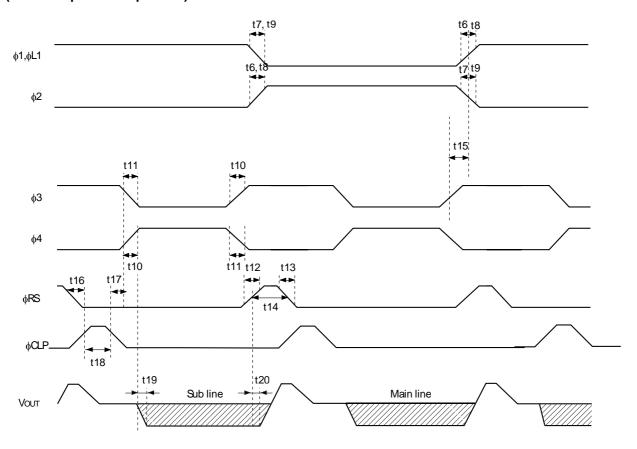


Note) The transfer pulses $(\phi 1, \phi 2)$ must have more than 10797 cycles. Vout indicates Vout-R, Vout-G, Vout-B.

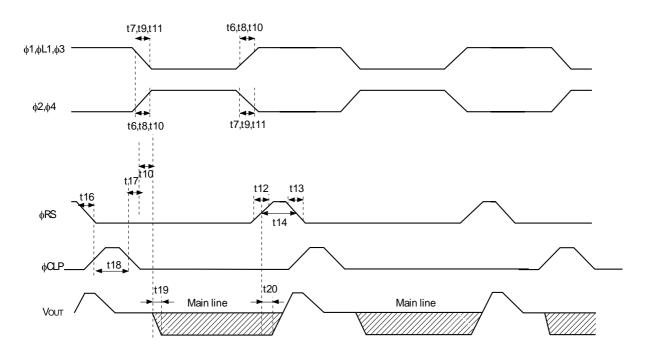
Clock Timing Chart5 2400 DPI Staggered



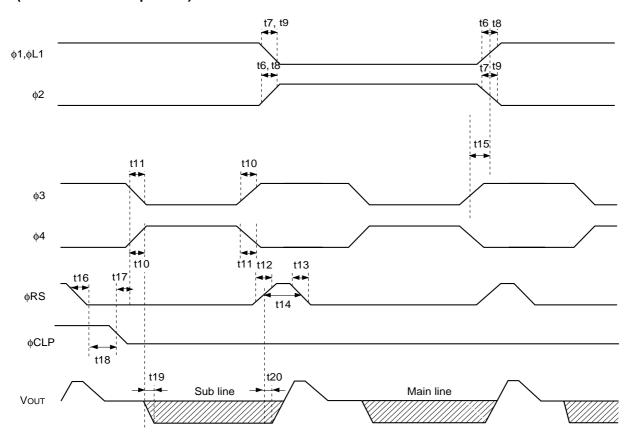
ClockTiming Chart 6 (2400 DPI pixel clamp mode)



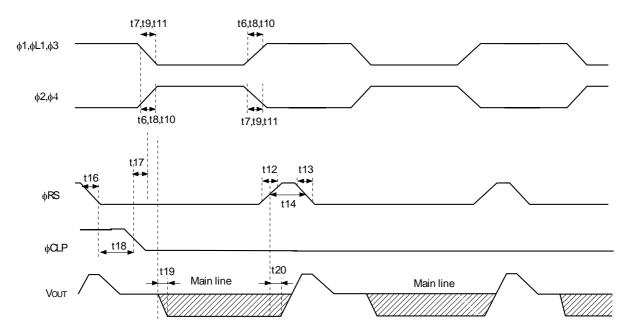
ClockTiming Chart 7 (1200 DPI pixel clamp mode)



ClockTiming Chart 8 (2400 DPI line clamp mode)



ClockTiming Chart 9 (1200 DPI line clamp mode)

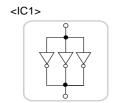


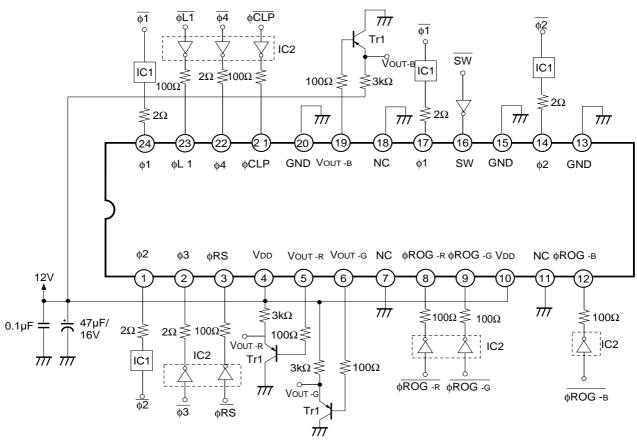
Clock Pulse Recommended Timing

Item	Symbol	Min.	Тур.	Max.	Unit
φROG, φ1 pulse timing	t1	50	100		ns
φROG pulse high level period	t2	5	10		μs
φROG, φ1 pulse timing	t3	3	5		μs
φROG pulse rise time	t 4	0	5	10	ns
φROG pulse fall time	t5	0	5	10	ns
φ1 pulse rise time/φ2 pulse fall time	t6	0	50	80	ns
φ1 pulse fall time/φ2 pulse rise time	t7	0	50	80	ns
φL1 pulse rise time/φ2 pulse fall time	t8	0	10	30	ns
φL1 pulse fall time/φ2 pulse rise time	t9	0	10	30	ns
φ3 pulse rise time/φ4 pulse fall time	t10	0	10	30	ns
φ3 pulse fall time/φ4 pulse rise time	t11	0	10	30	ns
φRS pulse rise time	t12	0	10	30	ns
φRS pulse fall time	t13	0	10	30	ns
φRS pulse high level period	t14	30	100*1		ns
φL1,φ2-φ3 pulse timing	t15	0	10		ns
φRS,φCLP pulse timing	t16	0	250* 1		ns
φCLP,φL1,φ3 pulse timing	t17	60	250*1		ns
φCLP pulse high level period	t18	20	100		ns
Signal output delay time	t 19		40		ns
	t20		20		ns

^{*1} These timing is the recommended condition under f ϕ RS = 1MHz.

Application Circuit*





* Data rate fors = 1MHz

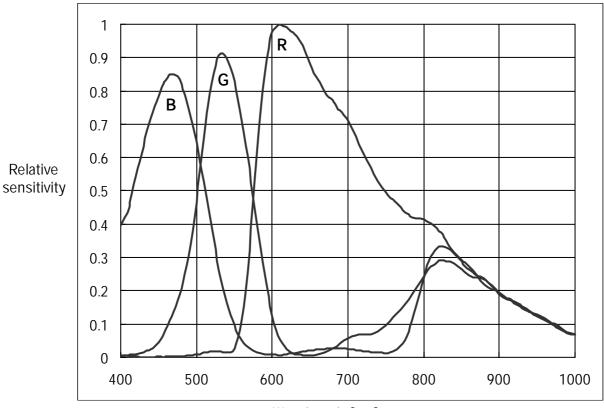
IC1: 74AC04 × 3pcs IC2: 74HC04 Tr1: 2SA1175

Application circuits shown are typical examples illustrating the operation of the devices. Sony cannot assume responsibility for any problems arising out of the use of these circuits or for any infringement of third party patent and other right due to same.

Example of Representative Characteristics

<2400DPI>

Spectral sensitivity characteristics (Standard characteristics)



Wavelength [nm]

Notes of Handling

1) Static charge prevention

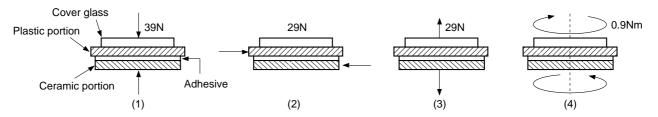
CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.

- a) Either handle bare handed or use non chargeable gloves, clothes or material. Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) Ionized air is recommended for discharge when handling CCD image sensor.
- e) For the shipment of mounted substrates, use boxes treated for prevention of static charges.

2) Notes on Handling CCD Packages

The following points should be observed when handling and installing packages.

- a) Remain within the following limits when applying static load to the package:
 - (1) Compressive strength: 39N/surface (Do not apply load more than 0.7mm inside the outer perimeter of the glass portion.)
 - (2) Shearing strength: 29N/surface
 - (3) Tensile strength: 29N/surface
 - (4) Torsional strength: 0.9Nm



- b) In addition, if a load is applied to the entire surface by a hard component, bending stress may be generated and the package may fracture, etc., depending on the flatness of the ceramic portion. Therefore, for installation, either use an elastic load, such as a spring plate, or an adhesive.
- c) Be aware that any of the following can cause the package to crack or dust to be generated.
 - (1) Applying repetitive bending stress to the external leads.
 - (2) Applying heat to the external leads for an extended period of time with soldering iron.
 - (3) Rapid cooling or heating.
 - (4) Prying the plastic portion and ceramic portion away at a support point of the adhesive layer.
 - (5) Applying the metal a crash or a rub against the plastic portion.
 - Note that the preceding notes should also be observed when removing a component from a board after it has already been soldered.
- d) The notch of the plastic portion is used for directional index, and that can not be used for reference of fixing. In addition, the cover glass and seal resin may overlap with the notch or ceramic may overlap with the notch of the plastic portion.

3) Soldering

- a) Make sure the package temperature does not exceed 80°C.
- b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a 30W soldering iron with a ground wire and solder each pin in less then 2 seconds. For repairs and remount, cool sufficiently.
- c) To dismount an imaging device, do not use a solder suction equipment. When using an electric desoldering tool, ground the controller. For the control system, use a zero cross type.

- 4) Dust and dirt protection
 - a) Operate in clean environments.
 - b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
 - c) Clean with a cotton bud and ethyl alcohol if the glass surface is grease stained. Be careful not to scratch the glass.
 - d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.
- 5) Exposure to high temperatures or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.
- 6) CCD image sensors are precise optical equipment that should not be subject to mechanical shocks.

Package Outline

55.7 ± 0.3 42.72 (4µm X 10680Pixels) 7.830 ± 0.3 24 13 10.0 ± 0.3 10.16 5.0 ± 0.3 No.1 Pixel (Green) of 2400 DPI Н 12 (8.59) 4.0 ± 0.5 4.28 ± 0.5 5.334 1.778 0.46 0.3 (M)

24 pin DIP (400mil)

1. The height from the bottom to the sensor surface is 2.38 ± 0.3 mm.

2. The thickness of the cover glass is 0.7mm, and the refractive index is 1.5.

PACKAGE STRUCTURE

PACKAGE MATERIAL	Plastic, Ceramic
LEAD TREATMENT	GOLD PLATING
LEAD MATERIAL	42 ALLOY
PACKAGE MASS	5.43g
DRAWING NUMBER	LS-B41(E)